Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/016,184	LEIJTEN ET AL.
Examiner	Art Unit
Daniel Pan	2183

	SEARCHED				
Class	Subclass	Date	Examiner		
712	24 225 229	11/3/2005	DP		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
712	24 225 229	11/3/2005	DP	
Interference searched on West pgp		11/3/2005	DP	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
west (pgp uspat jpoabs epoabs derwent ibm) ieee npt 718/104 res. alloc. 711/143 writeback 711/215 microinst.	11/3/2005	DP		